

APPLICATION DATA SHEET

Electronic Version v14

Stylesheet Version v14.0

Title of Invention	[METHOD FOR DETECTING DEFECT OF SEMICONDUCTOR DEVICE]
Application Type :	regular, utility
Attorney Docket Number :	11535-US-PA
Correspondence address:	
Customer Number:	31561
	
Priority Data:	
Doc.No: 92122197; Country -TW ; Date: 2003-08-13 us-priority-not-claimed	
Inventors Information:	
<u>Inventor 1:</u>	
Applicant Authority Type:	Inventor
Citizenship:	TW
Name prefix:	Mr.
Given Name:	HOUNG-JIE
Family Name:	CHANG
Residence:	
City of Residence:	TAICHUNG COUNTY
Country of Residence:	TW
Address-1 of Mailing Address:	NO. 13, RENHE RD., HOULI TOWNSHIP
Address-2 of Mailing Address:	
City of Mailing Address:	TAICHUNG COUNTY
State of Mailing Address:	
Postal Code of Mailing Address:	
Country of Mailing Address:	TW
Phone:	
Fax:	
E-mail:	
<u>Inventor 2:</u>	
Applicant Authority Type:	Inventor

Citizenship:	TW
Name prefix:	Mr.
Given Name:	SHENG-JU
Family Name:	CHANG
Residence:	
City of Residence:	HSINCHU CITY
Country of Residence:	TW
Address-1 of Mailing Address:	NO. 116, LANE 1200, MINGHU RD.
Address-2 of Mailing Address:	
City of Mailing Address:	HSINCHU CITY
State of Mailing Address:	
Postal Code of Mailing Address:	
Country of Mailing Address:	TW
Phone:	
Fax:	
E-mail:	

Attorney Information:

practitioner(s) at Customer Number:

31561



as our attorney(s) or agent(s) to prosecute the application identified above, and to transact all business in the United States Patent and Trademark Office connected therewith.